

#### **General Description**

The MAX5100 parallel-input, voltage-output, quad 8-bit digital-to-analog converter (DAC) operates from a single +2.7V to +5.5V supply and comes in a space-saving 20-pin TSSOP package. Internal precision buffers swing Rail-to-Rail®, and the reference input range includes both ground and the positive rail. All four DACs share a common reference input.

The MAX5100 provides double-buffered logic inputs: four 8-bit buffer registers followed by four 8-bit DAC registers. This keeps the DAC outputs from changing during the write operation. An asynchronous control pin, LDAC, allows for simultaneous updating of the DAC registers.

The MAX5100 features a shutdown mode that reduces current to 1nA, as well as a power-on reset mode that resets all registers to code 00 hex on power-up.

#### **Features**

- ♦ +2.7V to +5.5V Single-Supply Operation
- ♦ Ultra-Low Supply Current 0.4mA while Operating 1nA in Shutdown Mode
- ♦ Ultra-Small 20-Pin TSSOP Package
- ♦ Ground to VDD Reference Input Range
- ♦ Output Buffer Amplifiers Swing Rail-to-Rail
- ♦ Double-Buffered Registers for Synchronous **Updating**
- ♦ Power-On Reset Sets All Registers to Zero

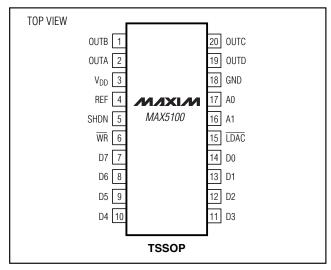
### **Ordering Information**

PART	TEMP. RANGE	PIN-PACKAGE	INL (LSB)
MAX5100AEUP	-40°C to +85°C	20 TSSOP	±1
MAX5100BEUP	-40°C to +85°C	20 TSSOP	±2

## **Applications**

Digital Gain and Offset Adjustments Programmable Attenuators Portable Instruments Power-Amp Bias Control

### **Pin Configuration**



Rail-to-Rail is a registered trademark of Nippon Motorola, Ltd.

MIXIM

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#### **ABSOLUTE MAXIMUM RATINGS**

V <sub>DD</sub> to GND	
D_, A_, WR, SHDN, LDAC to GND	0.3V to +6V
REF to GND	$-0.3V$ to $(V_{DD} + 0.3V)$
OUT_ to GND	0.3V to V <sub>DD</sub>
Maximum Current into Any Pin	±50mA
Continuous Power Dissipation (T <sub>A</sub> = +70°C	C)
20-Pin TSSOP (derate 7.0mW/°C abov	e +70°C)559mW

Operating Temperature Range	
MAX5100_EUP	40°C to +85°C
Maximum Junction Temperature	+150°C
Storage Temperature Range	65°C to +150°C
Lead Temperature (soldering, 10sec)	+300°C

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### **ELECTRICAL CHARACTERISTICS**

 $(V_{DD} = V_{REF} = +2.7V \text{ to } +5.5V, R_L = 10k\Omega, C_L = 100pF, T_A = T_{MIN} \text{ to } T_{MAX}, \text{ unless otherwise noted.}$  Typical values are at  $V_{DD} = V_{REF} = +3V$  and  $T_A = +25^{\circ}C.)$ 

PARAMETER	SYMBOL	CONDITIONS			TYP	MAX	UNITS
STATIC ACCURACY	•			1			
Resolution						8	Bits
Integral Naplingarity (Nato 1)	INL	MAX5100A				±1	- LSB
Integral Nonlinearity (Note 1)	IINL	MAX5100B	MAX5100B			±2	
Differential Nonlinearity (Note 1)	DNL	Guaranteed monotoni	ic			±1	LSB
Zero-Code Error	ZCE	Code = 00 hex				±20	mV
Zero-Code-Error Supply Rejection		Code = 00 hex, V <sub>DD</sub> =	= 2.7V to 5.5V			10	mV
Zero-Code Temperature Coefficient		Code = 00 hex			±10		μV/°C
Gain Error (Note 2)		Code = F0 hex				±1	%
Gain-Error Temperature Coefficient		Code = F0 hex			±0.001		LSB/°C
		Code = FF hex	$V_{DD} = 2.7V \text{ to } 3.6V,$ $V_{REF} = 2.5V$			1	1.00
Power-Supply Rejection			$V_{DD} = 4.5V \text{ to } 5.5V,$ $V_{REF} = 4.096V$			1	- LSB
REFERENCE INPUT				ı			
Input Voltage Range				0		V <sub>DD</sub>	V
Input Resistance				320	460	600	kΩ
Input Capacitance					15		pF
DAC OUTPUTS							
Output Voltage Range		R <sub>L</sub> = ∞		0		V <sub>REF</sub>	V
DIGITAL INPUTS							
Input High Voltage	VIH	$V_{DD} = 2.7V \text{ to } 3.6V$		2			V
		$V_{DD} = 3.6V \text{ to } 5.5V$		3			-
Input Low Voltage	VIL					0.8	V
Input Current	I <sub>IN</sub>	$V_{IN} = V_{DD}$ or GND				±1.0	μΑ
Input Capacitance	CIN				10		pF

#### **ELECTRICAL CHARACTERISTICS (continued)**

 $(V_{DD} = V_{REF} = +2.7V \text{ to } +5.5V, R_L = 10k\Omega, C_L = 100pF, T_A = T_{MIN} \text{ to } T_{MAX}, \text{ unless otherwise noted.}$  Typical values are at  $V_{DD} = V_{REF} = +3V$  and  $T_A = +25^{\circ}C.)$ 

PARAMETER	SYMBOL	CONI	MIN	TYP	MAX	UNITS	
DYNAMIC PERFORMANCE							
Output Voltage Slew Rate		From code 00 to code F0 hex			0.6		V/µs
Output Settling Time (Note 3)		To 1/2LSB, from code	e 10 to code F0 hex	6		μs	
Channel-to-Channel Isolation (Note 4)		Code 00 to code FF h	nex		500		nVs
Digital Feedthrough (Note 5)		Code 00 to code FF h	nex	0.5		nVs	
Digital-to-Analog Glitch Impulse		Code 80 hex to code	7F hex	90		nVs	
Signal-to-Noise plus Distortion	CINIAD	V <sub>REF(DC)</sub> = 1.5V, V <sub>DD</sub> = 3V, code = FF hex	REF = 2.5Vp-p at 1kHz		70		-ID
Ratio	SINAD		REF = 2.5Vp-p at 10kHz		60		- dB
Multiplying Bandwidth		REF = 0.5Vp-p, V <sub>REF(DC)</sub> = 1.5V, V <sub>DD</sub> = 3V, -3dB bandwidth		650		kHz	
Wideband Amplifier Noise					60		μV <sub>RMS</sub>
Shutdown Recovery Time	tsdr	To ±1/2LSB of final value of VOUT			13		μs
Time to Shutdown	tsdn	I <sub>DD</sub> < 5μA			20		μs
POWER SUPPLIES							
Power-Supply Voltage	V <sub>DD</sub>			2.7		5.5	V
Supply Current (Note 6)	I <sub>DD</sub>				370	700	μΑ
Shutdown Current					0.001	1	μΑ
DIGITAL TIMING (Figure 1) (Note 7)							
Address to WR Setup	tas			5			ns
Address to WR Hold	t <sub>AH</sub>			0			ns
Data to WR Setup	tDS			25			ns
Data to WR Hold	tDH			0			ns
WR Pulse Width	twR			20			ns
LDAC Pulse Width (Note 8)	t <sub>LD</sub>			20			ns

- Note 1: Reduced digital code range (code 00 hex to code F0 hex) due to swing limitations when the output amplifier is loaded.
- Note 2: Gain error is: [100 (VF0,meas ZCE VF0,ideal) / VREF]. Where VF0,meas is the DAC output voltage with input code F0 hex, and VF0,ideal is the ideal DAC output voltage with input code F0 hex (i.e., VREF 240 / 256).
- **Note 3:** Output settling time is measured from the 50% point of the falling edge of  $\overline{WR}$  to  $\pm 1/2LSB$  of  $V_{OUT}$ 's final value.
- **Note 4:** Channel-to-channel isolation is defined as the glitch energy at a DAC output in response to a full-scale step change on any other DAC output. The measured channel has a fixed code of 80 hex.
- Note 5: Digital feedthrough is defined as the glitch energy at any DAC output in response to a full-scale step change on all eight data inputs with WR at VDD.
- **Note 6:**  $R_L = \infty$ , digital inputs at GND or  $V_{DD}$ .
- Note 7: Timing measurement reference level is (VIH + VIL) / 2.
- Note 8: If LDAC is activated prior to WR's rising edge, it must stay low for tLD (or longer) after WR goes high.

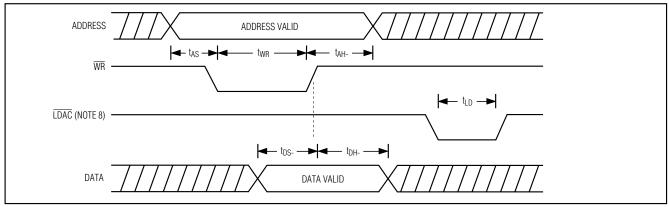
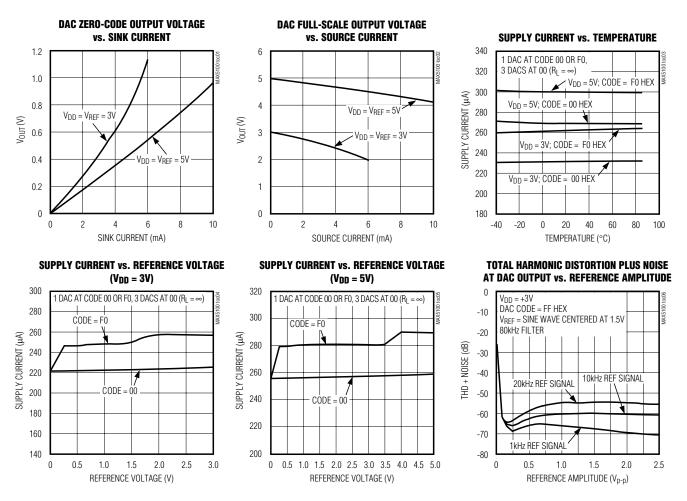


Figure 1. Timing Diagram

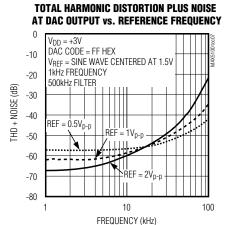
### Typical Operating Characteristics

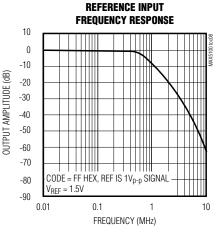
 $(V_{DD} = V_{REF} = +3V, R_L = 10k\Omega, C_L = 100pF, code = FF hex, T_A = +25^{\circ}C, unless otherwise noted.)$ 

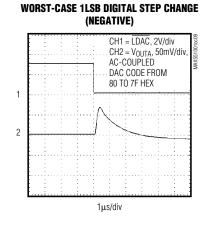


### **Typical Operating Characteristics (continued)**

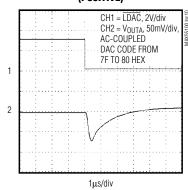
 $(V_{DD} = V_{RFF} = +3V, R_L = 10k\Omega, C_L = 100pF, code = FF hex, T_A = +25^{\circ}C, unless otherwise noted.)$ 



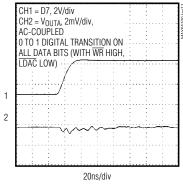




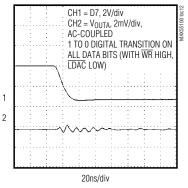
# WORST-CASE 1LSB DIGITAL STEP CHANGE (POSITIVE)



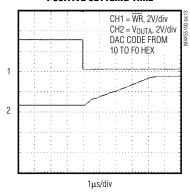




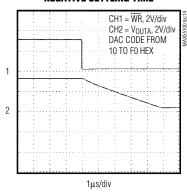
# DIGITAL FEEDTHROUGH GLITCH IMPULSE (1 TO 0 DIGITAL TRANSITION)



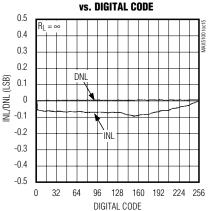
#### POSITIVE SETTLING TIME



#### **NEGATIVE SETTLING TIME**



## INTEGRAL AND DIFFERENTIAL NONLINEARITY



#### **Pin Description**

PIN	NAME	FUNCTION
1	OUTB	DAC B Voltage Output
2	OUTA	DAC A Voltage Output
3	V <sub>DD</sub>	Positive Supply Voltage. Bypass VDD to GND using a 0.1µF capacitor.
4	REF	Reference Voltage Input
5	SHDN	Shutdown. Connect SHDN to GND for normal operation.
6	WR	Write Input (active low). Use WR to load data into the DAC input latch selected by A0 and A1.
7–14	D7-D0	Data Inputs 7–0
15	LDAC	Load DAC Input (active low). Drive the asynchronous LDAC input low to transfer the contents of all input latches to their respective DAC latch.
16	A1	DAC Address Select Bit (MSB)
17	A0	DAC Address Select Bit (LSB)
18	GND	Ground
19	OUTD	DAC D Voltage Output
20	OUTC	DAC C Voltage Output

## **Detailed Description**

### **Digital-to-Analog Section**

The MAX5100 uses a matrix decoding architecture for the DACs. The external reference voltage is divided down by a resistor string placed in a matrix fashion. Row and column decoders select the appropriate tab from the resistor string to provide the needed analog voltages. The resistor network converts the 8-bit digital input into an equivalent analog output voltage in proportion to the applied reference voltage input. The resistor string presents a code-independent input impedance to the reference and guarantees a monotonic output.

The device can be used in multiplying applications. The voltages are buffered by rail-to-rail op amps connected in a follower configuration to provide a rail-to-rail output. The functional block diagram for the MAX5100 is shown in Figure 2.

#### **Low-Power Shutdown Mode**

The MAX5100 features a shutdown mode that reduces current consumption to 1nA. A high voltage on the shutdown pin shuts down the DACs and the output amplifiers. In shutdown mode, the output amplifiers enter a high-impedance state. When bringing the

device out of shutdown, allow 13µs for the output to stabilize.

#### **Output Buffer Amplifiers**

The DAC outputs are internally buffered by precision amplifiers with a typical slew rate of 0.6V/µs. The typical settling time to  $\pm 1/2LSB$  at the output is 6µs when loaded with  $10k\Omega$  in parallel with 100pF.

#### **Reference Input**

The MAX5100 provides a code-independent input impedance on the REF input. The input impedance is typically  $460k\Omega$  in parallel with 15pF, and the reference input voltage range is 0 to VDD. The reference input accepts positive DC signals as well as AC signals with peak values between 0 and VDD. The voltage at REF sets the full-scale output voltage for the DAC. The output voltage (VOUT) for any DAC is represented by a digitally programmable voltage source as follows:

$$V_{OUT} = (N_B \cdot V_{REF}) / 256$$

where  $N_{\mbox{\footnotesize B}}$  is the numeric value of the DAC binary input code.

#### **Digital Inputs and Interface Logic**

In the MAX5100, address lines A0 and A1 select the DAC that receives data from D0-D7, as shown in Table 1.

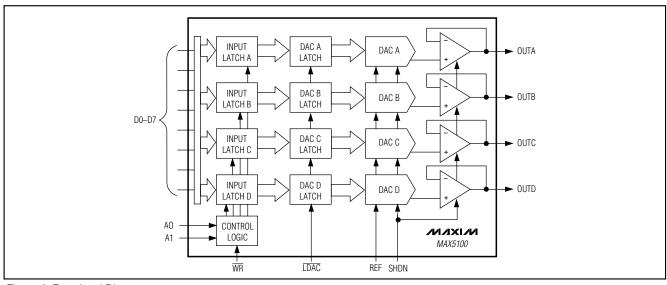


Figure 2. Functional Diagram

#### **Table 1. MAX5100 Address Table (Partial)**

LDAC	WR	<b>A</b> 1	A0	LATCH STATE
Н	Н	Х	Χ	Input and DAC data latched
Н	L	L	L	DAC A input latch transparent
L	Н	Х	Х	All 4 DACs' DAC latches transparent
L	L	L	L	DAC A input registers transparent and all 4 DACs' DAC latches transparent
Н	L	L	Н	DAC B input latch transparent
Н	L	Н	L	DAC C input latch transparent
Н	L	Н	Н	DAC D input latch transparent

H = High state, L = Low state, X = Don't care

When  $\overline{WR}$  is low, the addressed DAC's input latch is transparent. Data is latched when  $\overline{WR}$  is high.

The MAX5100 \(\overline{LDAC}\) feature allows simultaneous updating of all four DACs. \(\overline{LDAC}\) low latches the data in the data registers to the DAC registers. If simultaneous updating is not required, tie \(\overline{LDAC}\) low to keep the DAC latches transparent. If \(\overline{WR}\) and \(\overline{LDAC}\) are low simultaneously, avoid output glitches by ensuring that data is valid before the two signals go low. When the device powers up (i.e., VDD ramps up), all latches are internally preset with code 00 hex.

### Applications Information

#### **External Reference**

The reference source resistance must be considerably less than the reference input resistance. To keep within 1LSB error in an 8-bit system, Rs must be less than RREF / 256. Hence, maintain a value of Rs <1k $\Omega$  to ensure 8-bit accuracy. If VREF is DC only, bypass REF to GND with a 0.1 $\mu$ F capacitor. Values greater than this improve noise rejection.

#### **Power Sequencing**

The voltage applied to REF should not exceed  $V_{DD}$  at any time. If proper power sequencing is not possible, connect an external Schottky diode between REF and  $V_{DD}$  to ensure compliance with the absolute maximum ratings.

#### Power-Supply Bypassing and Ground Management

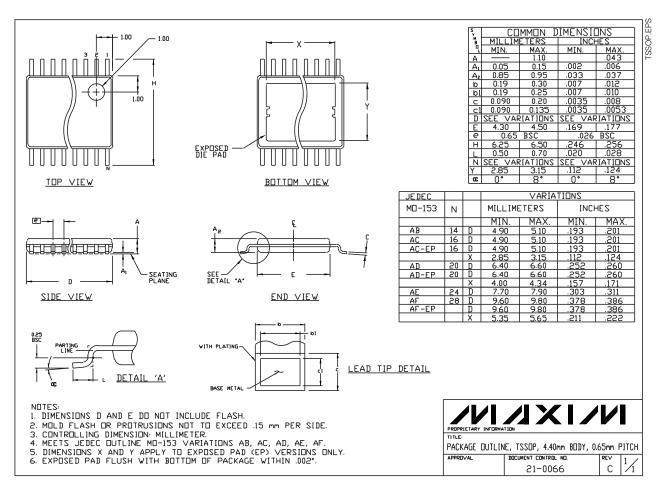
Digital or AC transient signals on GND can create noise at the analog output. Return GND to the highest-quality ground available. Bypass  $V_{DD}$  with a  $0.1\mu\text{F}$  capacitor, located as close to  $V_{DD}$  and GND as possible.

Careful PC board ground layout minimizes crosstalk between the DAC outputs and digital inputs.

#### **Chip Information**

**TRANSISTOR COUNT: 6848** 

### **Package Information**



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